NSN 6625-01-581-4169

Fiig: T228-a

Semiconductor Device Test Set - Page 1 of 1



View Online at https://aerobasegroup.com/nsn/6625-01-581-4169 Width: 11.100 inches Ac Voltage Rating: 100.0 volts or 115.0 volts or 230.0 volts Frequency Rating: Between 50.0 hertz and 60.0 hertz Depth: 8.500 inches **Electrical Power Source Relationship:** Operating Inclosure Feature: Single item w/housing **Test Type For Which Designed:** Resistance, capacitance, inductance **Operating Test Capability:** Frequencies 20, 50, 60, 200, 500, and 2khz; voltages 200milli, 3, 5, 10, 15, and 20v; resistance 10, 50, 100, 500, 1k, 5k, 10k, 50k, 100k ohms Phase: Single **Functional Classification:** Aa-1.3 **Functional Description:** Used to test passive devices, diodes, transistors, gated devices, optoelectronic devices, and integrated circuits Height: 4.400 inches **Entry Date:** 10-01-14 **Relationship To Similar Equipment:** Tracker 2800s can scan multi-pin Shelf Life: N/a **Unit Of Measure: Demilitarization:** Yes - demil/mli